

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

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IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 22.0004 Issue No.: 2 Status: Current

Supersedes: IECQ-L ULTW 22.0004 Issue 1 Issue Date: 2025/01/06 Org Issue: 2022/02/24

CB Reference No.: 20006234 ITL **Expiration: 2028/02/23**

WAFER WORKS CORP. (Semiconductor Material Analysis Laboratory)

No. 100, Longyuan 1st Rd., Longtan Science Park, Taoyuan 32542 Taiwan

The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

The analysis of semiconductor material.

See attached schedule.

- Attached Schedule: IECQ-L_ULTW_20006234 ITL. Schedule 01-06-25.pdf --

Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

8F, 23, Yuan Huan West Road, Feng Yuan Dist., Taichung City Taiwan

Authorized person:

Bob CHEN







The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 22.0004
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Appendix-1 (20006234 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
X-ray Topography(XRT)	QE-3-611
ICP-MS	QE-3-607
u-PCD	QE-3-610
Surface Photo Voltage (SPV)	QE-3-608

Technical Reviewer of DQS: Faul Yay Date: 01/06/2025

